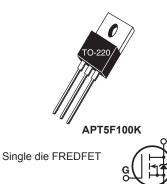




1000V, 5A 2.8Ω Max, Trr ≤ 155nS

N-Channel FREDFET

POWER MOS 8® is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- · Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I _D	Continuous Drain Current @ T _C = 25°C	5	
	Continuous Drain Current @ T _C = 100°C	3	Α
I _{DM}	Pulsed Drain Current ^①	20	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ©	310	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	3	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P_{D}	Total Power Dissipation @ T _C = 25°C			225	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			035	035 °C/W	
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15			
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	- °C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight -		0.22		OZ	
			6.2		g	
Torque	Mounting Targue / TO 247 Package) 4 40 or M2 percy			10	in·lbf	
	Mounting Torque (TO-247 Package), 4-40 or M3 screw			1.1	N·m	

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$	1000			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I_D = 250 μ A		1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	$V_{GS} = 10V, I_D = 3A$		2.4	2.8	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	\\ -\\ -0.5m\	2.5	4	5	V
$\Delta V_{GS(th)} / \Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_{D} = 0.5 \text{mA}$		-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V$ $T_J = 25^{\circ}C$			250	
DSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ $T_J = 125^{\circ}C$			1000	μA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dvnamic Characteristics

T₁ = 25°C unless otherwise specified

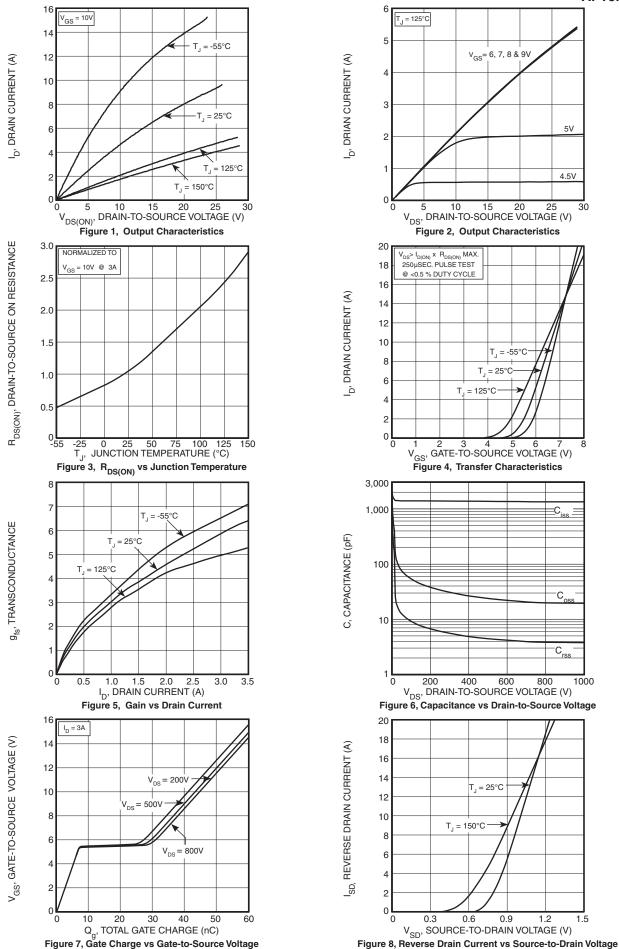
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 3A		5.6		S	
C _{iss}	Input Capacitance	V 0V V 0FV		1409			
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		19			
C _{oss}	Output Capacitance	1 - 11/11/12		118			
C _{o(cr)} ④	Effective Output Capacitance, Charge Related	V = 0V V = 0V to 500V		48		pF	
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	V _{GS} = 0V, V _{DS} = 0V to 500V		25			
Q_g	Total Gate Charge	V 04:40V 1 04		43			
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 6A,$		7.6		nC	
Q_{gd}	Gate-Drain Charge	V _{DS} = 500V		21			
t _{d(on)}	Turn-On Delay Time	Resistive Switching		23			
t _r	Current Rise Time	V _{DD} = 666V, I _D = 3		21] nc	
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 2.2\Omega^{\textcircled{6}}, V_{GG} = 15V$		72		ns	
t _f	Current Fall Time			21			

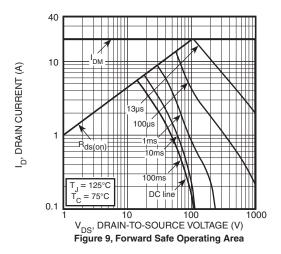
Source-Drain Diode Characteristics

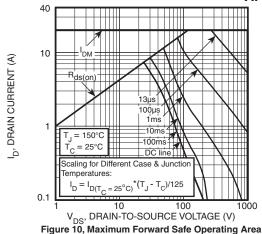
Symbol	Parameter	Test Cond	Min	Тур	Max	Unit	
Is	Continuous Source Current (Body Diode)	MOSFET symbol showing the				5.4	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	SU FIS			20	A
V_{SD}	Diode Forward Voltage	$I_{SD} = 3A, T_{J} = 25^{\circ}C, V_{GS} = 0V$				1.3	V
t _{rr}	Daviana Daasvan Tima		T _J = 25°C		130	155	20
rr	Reverse Recovery Time	,	T _J = 125°C		199	247	ns
Q _{rr}	Daviana Daasvani Chare	I _{SD} = 3A ^③	T _J = 25°C		0.4		
rr	Reverse Recovery Charge	di _{SD} /dt = 100A/μs	T _J = 125°C		0.8		μC
ı		V _{DD} = 100V	T _J = 25°C		6		Λ
'rrm	Reverse Recovery Current		T _J = 125°C		8		A
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 3A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 400V$, $T_J = 125^{\circ}C$				25	V/ns

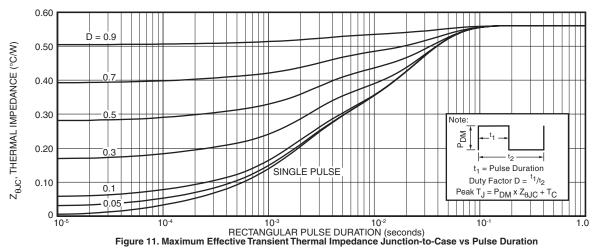
- ① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25$ °C, L = 69mH, $R_G = 25\Omega$, $I_{AS} = 3A$.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
 C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -3.43E-8/V_{DS}^2 + 1.44E-8/V_{DS} + 5.38E-11.
- \bigcirc R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

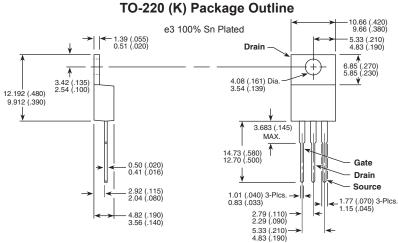
Microsemi reserves the right to change, without notice, the specifications and information contained herein.











Dimensions in Millimeters and (Inches)